

May 2001

FQPF50N06L

60V LOGIC N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 32.6A, 60V, $R_{DS(on)}$ = 0.021 Ω @V_{GS} = 10 V Low gate charge (typical 24.5 nC)
- Low Crss (typical 90 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating



Absolute Maximum Ratings T_C = 25°C unless otherwise noted

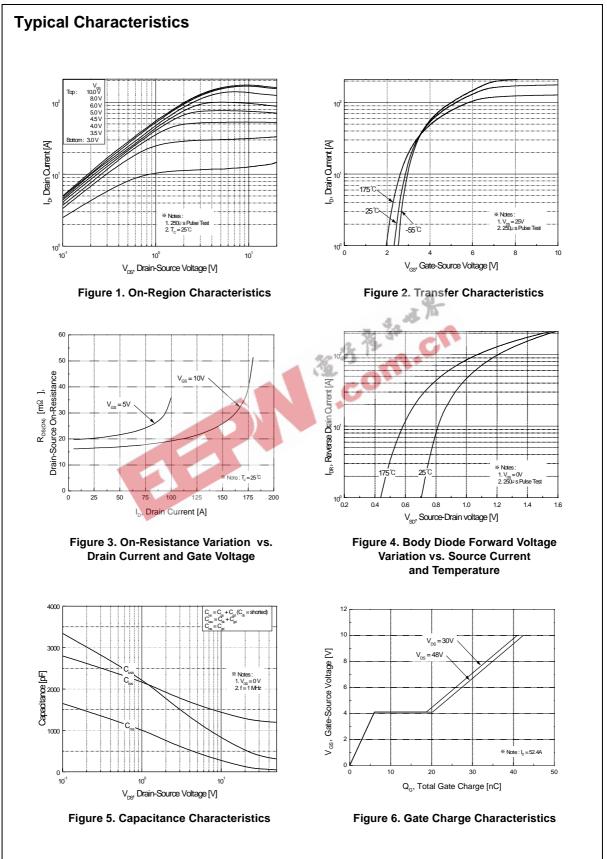
Symbol	Parameter		FQPF50N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	32.6	А
	- Continuous (T _C = 100	O°C)	23.1	А
I _{DM}	Drain Current - Pulsed	(Note 1)	130	А
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1000	mJ
I _{AR}	Avalanche Current	(Note 1)	32.6	A
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		47	W
	- Derate above 25°C		0.31	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

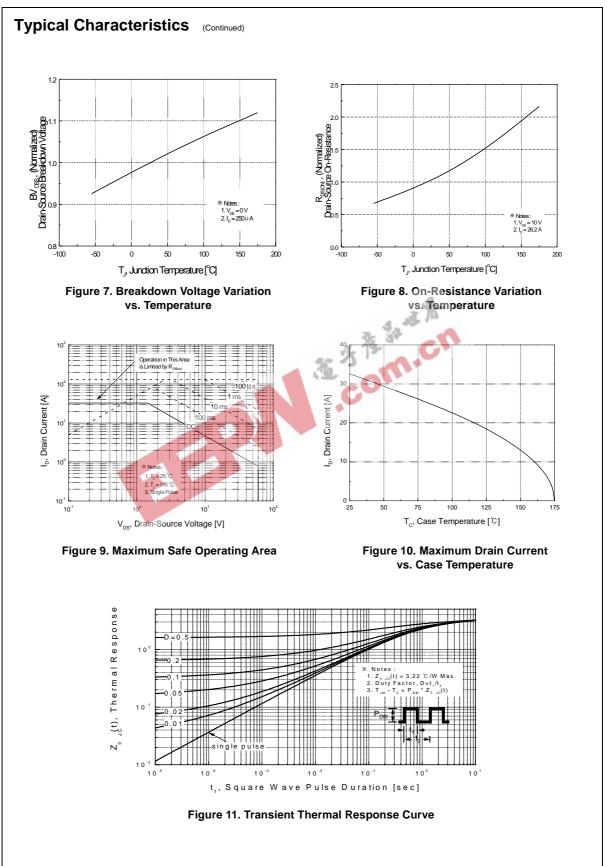
Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.22	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	aracteristics		•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 16.3 A		0.017	0.021	_
-(-,	On-Resistance	$V_{GS} = 5 \text{ V}, I_{D} = 16.3 \text{ A}$		0.020	0.025	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 25 V, I _D = 16.3 A (Note 4)		35		S
Dynam	ic Characteristics	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$	No.			
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$	A	1250	1630	pF
C _{oss}	Output Capacitance	f = 1.0 MHz	172	445	580	pF
C _{rss}	Reverse Transfer Capacitance			90	120	pF
Switch	ing Characteristics	CO.				
t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 26.2 A,		20	50	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		380	770	ns
	Turn-Off Delay Time	1.G = 3 -1		80	170	ns
$t_{d(off)}$				145	300	ns
t _{d(off)}	Turn-Off Fall Time	(Note 4, 5)		170		
	Turn-Off Fall Time Total Gate Charge	, , , ,		24.5	32	nC
t _f		(Note 4, 5) V _{DS} = 48 V, I _D = 52.4 A, V _{GS} = 5 V			32	_
t _f Q _g	Total Gate Charge	V _{DS} = 48 V, I _D = 52.4 A,		24.5		nC
t _f Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge	$V_{DS} = 48 \text{ V}, I_{D} = 52.4 \text{ A},$ $V_{GS} = 5 \text{ V}$ (Note 4, 5)		24.5 6		nC nC
$egin{array}{l} t_{\mathrm{f}} & & & \\ Q_{\mathrm{g}} & & & \\ Q_{\mathrm{gs}} & & & \\ Q_{\mathrm{gd}} & & & & \\ & & & & \\ & & & & \\ & & & &$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DS} = 48 V, I_{D} = 52.4 A, V_{GS} = 5 V (Note 4, 5)		24.5 6		nC nC
$egin{array}{ll} t_{f} & & & \\ Q_{g} & & & \\ Q_{gs} & & & \\ Q_{gd} & & & \\ \hline \textbf{Drain-S} & & & \\ I_{SM} & & & \\ \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics ar	V _{DS} = 48 V, I _D = 52.4 A, V _{GS} = 5 V (Note 4, 5) Ad Maximum Ratings ode Forward Current Forward Current		24.5 6 14.5		nC nC
t _f Q _g Q _{gs} Q _{gd} Drain-S	Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	V_{DS} = 48 V, I_{D} = 52.4 A, V_{GS} = 5 V (Note 4, 5) and Maximum Ratings and Forward Current Forward Current V_{GS} = 0 V, I_{S} = 32.6 A		24.5 6 14.5	32.6	nC nC nC
$egin{array}{ll} t_{f} & & & \\ Q_{g} & & & \\ Q_{gs} & & & \\ Q_{gd} & & & \\ \hline \textbf{Drain-S} & & & \\ I_{SM} & & & \\ \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics ar Maximum Continuous Drain-Source Diode Maximum Pulsed Drain-Source Diode F	V _{DS} = 48 V, I _D = 52.4 A, V _{GS} = 5 V (Note 4, 5) Ad Maximum Ratings ode Forward Current Forward Current		24.5 6 14.5	32.6 130	nC nC nC

 $[\]label{eq:Notes:1} \begin{array}{ll} \textbf{Notes:} \\ \textbf{1.} \ \text{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ \textbf{2.} \ \textbf{L} = \textbf{1.1mH, } \ \textbf{I}_{AB} = \textbf{32.6A}, \ \textbf{V}_{DD} = \textbf{25V}, \ \textbf{R}_{G} = \textbf{25} \ \textbf{\Omega}, \ \textbf{Starting} \ \ \textbf{T}_{J} = \textbf{25}^{\circ} \textbf{C} \\ \textbf{3.} \ \textbf{I}_{SD} \leq \textbf{52.4A}, \ \textbf{di/dt} \leq \textbf{3004} \ \textbf{J}_{DD} \leq \textbf{BV}_{DSS}, \ \textbf{Starting} \ \ \textbf{T}_{J} = \textbf{25}^{\circ} \textbf{C} \\ \textbf{4.} \ \textbf{Pulse Test: Pulse width} \leq \textbf{300\mu}, \ \textbf{Dut cycle} \leq \textbf{2\%} \\ \textbf{5.} \ \textbf{Essentially independent of operating temperature} \end{array}$

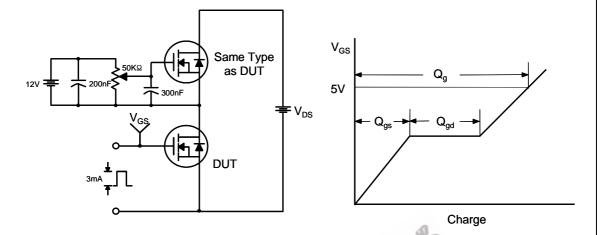


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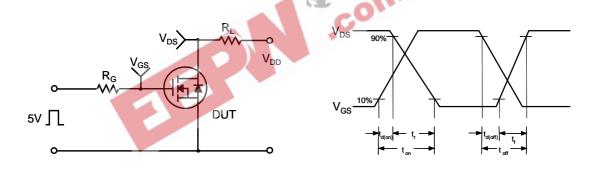


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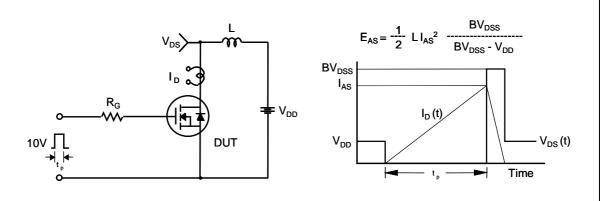
Gate Charge Test Circuit & Waveform



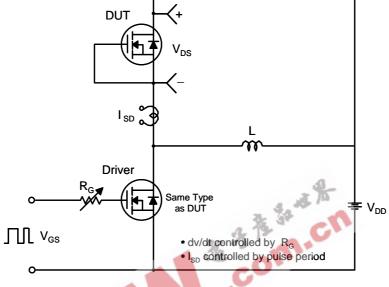
Resistive Switching Test Circuit & Waveforms

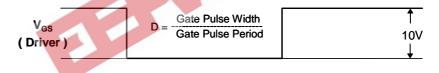


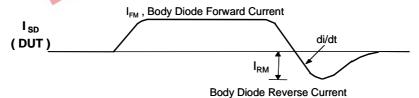
Unclamped Inductive Switching Test Circuit & Waveforms

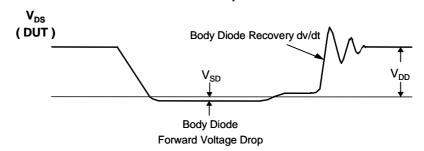


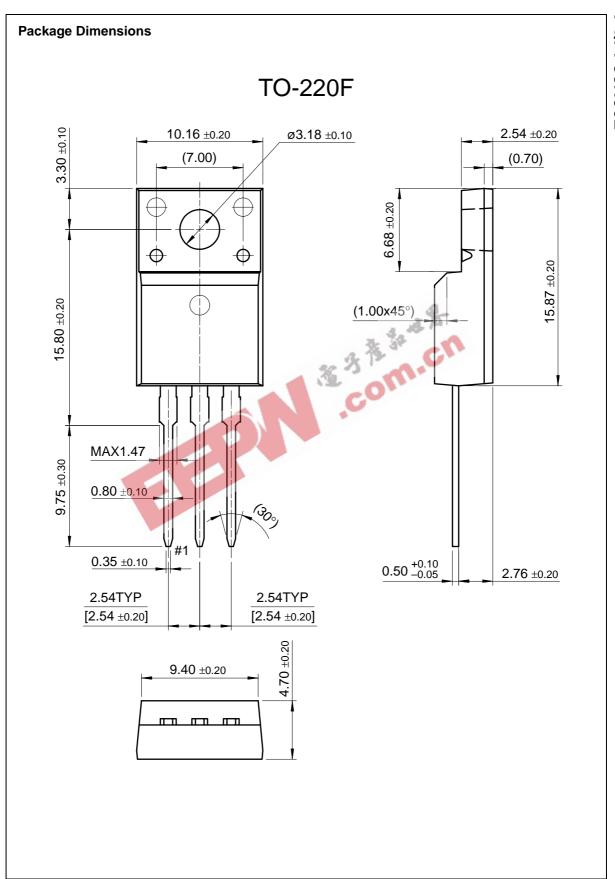
Peak Diode Recovery dv/dt Test Circuit & Waveforms











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